This year, International Test Conference celebrates its 31st year. As the premier conference for test technology, ITC continues its well-established format for Test WeekTM with two days of tutorials, a three-day conference program, followed by two days of workshops. This focused week of test has been assembled with the theme of Test Challenges of Faster and Smaller Technologies. Included in the week is a comprehensive set of papers, panels, lectures, exhibits, tutorials and workshops to support our theme. The technical program contains 41 sessions covering all aspects of chip, board and systems test. The theme of faster and smaller technologies weaves through many of the sessions and is especially evident in the number of topics exploring the GHz test domain.

Test Week starts with 16 tutorials including topics such as wafer testing, defects, mixed-signal test, BIST, board and system test. Knowledge needed by the test professional to keep up with the current developments in the state of the art. Next, a lighthearted panel—The Press Strikes Back. Come listen and ask questions of the press who cover the test industry. Following the panel and tutorials, join us Monday evening at our welcome reception.

Formal opening of the conference starts with the plenary session with a keynote address by Bruce Beers of IBM Microelectronics Division discussing historical and future test trends at the millennium. The invited speaker, Robert Aitken of Agilent Technologies, will then discuss the issues of design and test interfaces in the GHz domain.

The exhibit floor opens immediately following the plenary and is open concurrent with the technical program. It is filled with the major suppliers to the test industry. Come and see the newest equipment, software and services for solving your test problems. A complementary lunch is provided in the exhibit hall every day of the conference. The technical program contains interesting and high-quality material including design for diagnostics, production testing, ATE, test synthesis and test generation/fault simulation. There are many sessions and presentations supporting the conference theme — Test Challenges of Faster and Smaller Technologies. We have included this year a lecture series focused on defects, board and system test along with a special session on the IEEE P1500 standard work.

After the technical sessions on Monday afternoon, you have the opportunity to network with your Test Week friends at a complimentary pre-panel buffet. Immediately following are the traditional evening panel sessions. These sessions will engage you with a range of topics including ATE, defects and other challenging issues.

Tuesday and Wednesday, the technical program has sessions focused on the theme of the conference. Authors present material on defects, mixed-signal, crosstalk, ATE, memory, systems and many more state-of-the-art topics. Several sessions contain papers exploring issues in the high-speed and deep-submicron domains. The technical program this year is supplemented with a parallel-track lecture series and special sessions delving into issues of defects, board test, and system test, along with the emerging fields of SOC and FPGA testing.

Wednesday, we conclude the technical program with five afternoon panel sessions. Come join discussion of wireless, MEMS, and the topic Can DFT Totally Delete Functional Testing?

To close Test Week, we host three strong workshops; Test Resource Partitioning Workshop (TRP), Yield Optimization and Test Workshop (YOT), and System Test and Diagnosis Workshop (STaD).

Remember that Test Week is a good place for networking. This event brings together the active workers in test. What better way to exchange ideas, and forge new friendships? Fringe meetings are held throughout Test Week — you’ll find a list of them in the Conference Guide. These meetings have been formed by groups of interested test professionals who use the attraction of ITC to bring people from all over the world as a means to discuss focused issues such as standards. Check with program or steering committee members if you would like to organize such a meeting at next year’s event.

As you can see, the week is packed with many opportunities. We promise you that ITC 2000 will be the best yet. Explore the program, special sessions and exhibits in the world’s leading forum for the test professional.

We at ITC, including our many volunteers who give freely of their time to help create the program, welcome you to Atlantic City. We are sure that the program will contain many things of interest, but please be sure to fill-in the Session Feedback forms and fill the Evaluation Survey. The results of this survey are used to provide valuable feedback to both the Program Committee and Steering Committee. This information forms a basis for decisions on future conferences.

Thank you for helping to make ITC 2000 a success.

Douglas Young
General Chair

Wayne Needham
Program Chair